

Notice of References Cited	Application/Control No. 10/028,039	Applicant(s)/Patent Under Reexamination THATCHER ET AL.	
	Examiner Elias Desta	-Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6079038	04-1998	Huston et al.	714/724
	B	US-6418387	01-1999	Carney	702/81
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Niggemeyer et al., Parametric Built-In-Self-Test of VLSI Systems, January 1999, University of Hannover, pages 1-5.
	V	Hamada et al., A High-speed Boundary Search by Shmoo Plot for ULSI Memories, Janary 1993, IEEE, Vol: 4150, pages 4-9.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.